


<b>Search Notes</b> 	<b>Application/Control No.</b> 10728000	<b>Applicant(s)/Patent Under Reexamination</b> KIM ET AL.
	<b>Examiner</b> Pervan, Michael	<b>Art Unit</b> 2629

SEARCHED			
Class	Subclass	Date	Examiner
345	94-96, 100, 209-210, 690	7/5/2006	MP
above	updated	3/21/2007	MP
above	updated	8/30/2007	MP
above	updated	2/27/2008	MP

SEARCH NOTES		
Search Notes	Date	Examiner
see attached EAST search results	7/6/2006	MP
consulted Amr Awad for class/subclass search	6/29/2006	MP
see attached updated EAST search results	3/21/2007	MP
see attached updated EAST search results	8/30/2007	MP
see attached updated EAST search results	2/27/2008	MP
Interference search: ((first near5 (image near5 data)) and (second near5 (image near5 data)) and inversion and (common near5 voltage) and (even near5 pixel) and (odd near5 pixel)).clm.	2/27/2008	MP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
345	94-96, 100, 209-210, 690	2/27/2008	MP